

Dual Channel 12-Bit 500Msps Analog-to-Digital Converter

Check for Samples: ADS5404

FEATURES

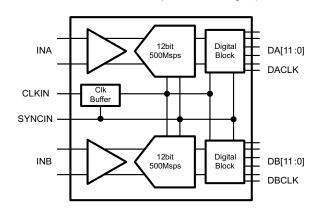
- Dual Channel
- 12-Bit Resolution
- Maximum Clock Rate: 500 Msps
- Low Swing Fullscale Input: 1.0 Vpp
- Analog Input Buffer with High Impedance Input
- Input Bandwidth (3 dB): >1.2 GHz
- Data Output Interface: DDR LVDS
- 196-Pin BGA Package (12x12mm)
- Power Dissipation: 910 mW/ch
- Performance at f_{in} = 230 MHz IF
 - SNR: 60.6 dBFS
 - SFDR: 77 dBc
- Performance at f_{in} = 700 MHz IF
 - SNR: 59.4 dBFS
 - SFDR: 70 dBc

APPLICATIONS • Test and Measurement Instrumentation

- Ultra-Wide Band Software Defined Radio
- Data Acquisition
- Power Amplifier Linearization
- Signal Intelligence and Jamming
- Radar and Satellite Systems
- Microwave Receivers

Device Part No.	Number of Channels	Speed Grade
ADS5402	2	800Msps
ADS5401	1	800Msps
ADS5404	2	500Msps
ADS5403	1	500Msps

DESCRIPTION The ADS5404 is a high linearity dual channel 12-bit, 500 MSPS analog-to-digital converter (ADC) easing front end filter design for wide bandwidth receivers. The analog input buffer isolates the internal switching of the onchip track-and-hold from disturbing the signal source as well as providing a high-impedance input. Optionally the output data can be decimated by two. Designed for high SFDR, the ADC has low-noise performance and outstanding spurious-free dynamic range over a large input-frequency range. The device is available in a 196-pin BGA package and is specified over the full industrial temperature range (–40°C to 85°C).



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AA

ADS5404



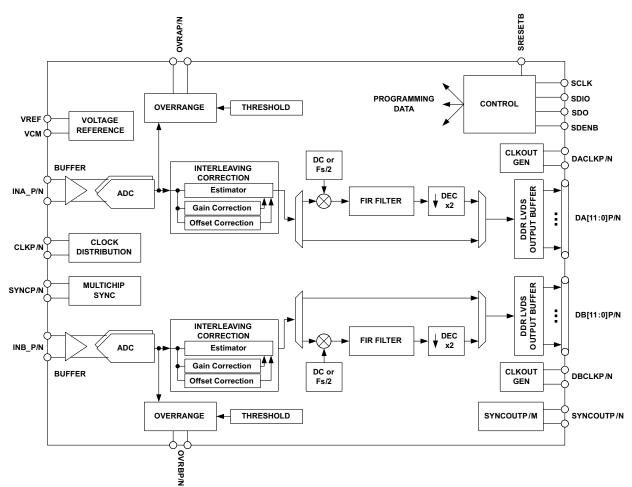
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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.



DETAILED BLOCK DIAGRAM



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	A	В	С	D	E	F	G	н	J	к	L	М	N	Ρ	
14	VREF	VCM	GND	INB_N	INB_P	GND	AVDDC	AVDDC	GND	INA_P	INA_N	GND	GND	CLKINP	14
13	SDENB	TEST MODE	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	CLKINN	13
12	SCLK	SRESET B	GND	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	GND	AVDD33	AVDD33	12
11	SDIO	ENABLE	GND	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	GND	AVDD18	AVDD18	11
10	SDO	IOVDD	GND	AVDD18	GND	GND	GND	GND	GND	GND	AVDD18	GND	NC	NC	10
9	DVDD	DVDD	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	SYNCN	SYNCP	9
8	DVDD	DVDD	DVDD	DVDD	GND	GND	GND	GND	GND	GND	DVDD	DVDD	DVDD	DVDD	8
7	DB0N	DB0P	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	NC	NC	7
6	DB1N	DB1P	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	NC	NC	6
5	DB2N	DB2P	OVRBN	OVRBP	GND	GND	GND	GND	GND	GND	OVRAN	OVRAP	SYNC OUTN	SYNC OUTP	5
4	DB3N	DB3P	DB8P	DB10P	NC	NC	NC	DA0P	DA2P	DA4P	DA6P	DA8P	NC	NC	4
3	DB4N	DB4P	DB8N	DB10N	NC	NC	NC	DA0N	DA2N	DA4N	DA6N	DA8N	DA11N	DA11P	3
2	DB5N	DB5P	DB7P	DB9P	DB11P	SYNC OUTP	DBCLKP	DACLKP	DA1P	DA3P	DA5P	DA7P	DA10N	DA10P	2
1	DB6N	DB6P	DB7N	DB9N	DB11N	SYNC OUTN	DBCLKN	DACLKN	DA1N	DA3N	DA5N	DA7N	DA9N	DA9P	1
	A	в	С	D	E	F	G	н	J	к	L	М	N	Р	

PINOUT INFORMATION

Figure 2. Pinout in DDR output mode (top down view)

PIN ASSIGNMENTS

	PIN		DECODIDITION			
NAME	NUMBER	I/O	DESCRIPTION			
INPUT/REFERE	ENCE					
INA_P/N	K14, L14	I	Analog ADC A differential input signal.			
INB_P/N	D14, E14	I	Analog ADC B differential input signal.			
		0	tput of the analog input common mode (nominally 1.9V). A $0.1\mu F$ capacitor to AGND is sommended.			
VREF	A14	I	Reference voltage input. A 0.1µF capacitor to AGND is recommended, but not required.			
CLOCK/SYNC						
CLKINP/N	P14, P13	I	Differential input clock			
SYNCP/N	P9, N9	I	Synchronization input. Inactive if logic low. When clocked in a high state initially, this is used for resetting internal clocks and digital logic and starting the SYNCOUT signal. Internal 100Ω termination.			
CONTROL/SEF	RIAL					
SRESET	B12	I	Serial interface reset input. Active low. Initialized internal registers during high to low transition. Asynchronous. Internal $50k\Omega$ pull up resistor to IOVDD.			

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PIN ASSIGNMENTS (continued)

	PIN		
NAME	NUMBER	I/O	DESCRIPTION
ENABLE	B11	I	Chip enable – active high. Power down function can be controlled through SPI register assignment. Internal $50k\Omega$ pull up resistor to IOVDD.
SCLK	A12	Ι	Serial interface clock. Internal $50k\Omega$ pull-down resistor.
SDIO	A11	I/O	Bi-directional serial data in 3 pin mode (default). In 4-pin interface mode (register x00, D16) the SDIO pin in an input only. Internal $50k\Omega$ pull-down.
SDENB	A13	I	Serial interface enable. Internal 50k Ω pull-down resistor.
SDO	A10	0	Uni-directional serial interface data in 4 pin mode (register x00, D16). The SDO pin is tristated in 3-pin interface mode (default). Internal $50k\Omega$ pull-down resistor.
TESTMODE	B13	-	Factory internal test, do not connect
DATA INTERFA	CE		
DA[11:0]P/N	P3, N3, P2, N2, P1, N1, M4, M3, M2, M1, L4, L3, L2, L1, K4, K3, K2, K1, J4, J3, J2, J1, H4, H3	ο	ADC A Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DB[11:0]P/N	E2, E1, D4, D3, D2, D1, C4, C3, C2, C1, B1, A1, B2, A2, B3, A3, B4, A4, B5, A5, B6, A6, B7, A7	0	ADC B Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DACLKP/N	H2, H1	0	DDR differential output data clock for Bus A. Register programmable to provide either rising or falling edge to center of stable data nominal timing.
DBCLKP/N	G2, G1	0	DDR differential output data clock for Bus B. Register programmable to provide either rising or falling edge to center of stable data nominal timing. Optionally Bus B can be latched with DACLKP/N.
SYNCOUTP/N	F2, F1, P5, N5	0	Synchronization output signal for synchronizing multiple ADCs. Can be disabled via SPI.
OVRAP/N	M5, L5	0	Bus A, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
OVRBP/N	D5, C5	0	Bus B, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
NC	E3, E4, F3, F4, G3, G4, N4, N6, N7, N10, P4, P6, P7, P10	_	Don't connect to pin
POWER SUPPL	Y		
AVDD33	D12, E12, F12, G12, H12, J12, K12, L12, N12, P12	I	3.3V analog supply
AVDDC	G14, H14	Ι	1.8V supply for clock input
AVDD18	D10, D11, E11, F11, G11, H11, J11, K11, L10, L11, N11, P11	I	1.8V analog supply
DVDD	A8, A9, B8, B9, C8, D8, L8, M8, N8, P8	I	1.8V supply for digital block
DVDDLVDS	C6, C7, D6, D7, L6, L7, M6, M7	I	1.8V supply for LVDS outputs
IOVDD	B10	Ι	1.8V for digital I/Os
GND		I	Ground



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	PACKAGE/ORDERING INFORMATION										
PRODUCT	PACKAGE- LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	ECO PLAN ⁽²⁾	LEAD/BALL FINISH	PACKAGE MARKING	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY			
				GREEN			ADS5404IZAY	Tray			
ADS5404	196-BGA	ZAY	–40°C to 85°C	(RoHS & no Sb/Br)		ADS5404I	ADS5404IZAYR	Tape and Reel			

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

		VA	ALUE	
		MIN	MAX	UNIT
Supply voltage range, AVDD3	3	-0.5	4	V
Supply voltage range, AVDDC	upply voltage range, AVDDC			V
Supply voltage range, AVDD1	-0.5	2.3	V	
Supply voltage range, DVDD		-0.5	2.3	V
Supply voltage range, DVDDLVDS		-0.5	2.3	V
Supply voltage range, IOVDD		-0.5	4	V
	INA/B_P, INA/B_N	-0.5	AVDD33 + 0.5	V
Veltere englied to input size	CLKINP, CLKINN	-0.5	AVDDC + 0.5	V
Voltage applied to input pins	SYNCP, SYNCN	-0.5	AVDD33 + 0.5	V
	SRESET, SDENB, SCLK, SDIO, SDO, ENABLE	-0.5	IOVDD + 0.5	V
Operating free-air temperature	e range, T _A	-40	85	°C
Operating junction temperatur	e range, T _J		150	°C
Storage temperature range		-65	150	°C
ESD, Human Body Model			2	kV

THERMAL INFORMATION

		ADS5404	
	THERMAL METRIC ⁽¹⁾	nFBGA	UNITS
		196 PINS	
θ_{JA}	Junction-to-ambient thermal resistance ⁽²⁾	37.6	
θ _{JCtop}	Junction-to-case (top) thermal resistance ⁽³⁾	6.8	
θ _{JB}	Junction-to-board thermal resistance ⁽⁴⁾	16.8	°C/W
Ψ _{JT}	Junction-to-top characterization parameter ⁽⁵⁾	0.2	
Ψ _{JB}	Junction-to-board characterization parameter ⁽⁶⁾	16.4	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.

(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.

(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDECstandard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.

(5) The junction-to-top characterization parameter, ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

(6) The junction-to-board characterization parameter, ψ_{JB} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

RECOMMENDED OPERATING CONDITIONS (continued)

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
-	Recommended operating junction temperature			105	°C
IJ	Maximum rated operating junction temperature ⁽¹⁾	125			
T _A	Recommended free-air temperature	-40	25	85	°C

(1) Prolonged use at this junction temperature may increase the device failure-in-time (FIT) rate.

ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^{\circ}$ C, full temperature range is $T_{MIN} = -40^{\circ}$ C to $T_{MAX} = 85^{\circ}$ C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ADC Clock	Frequency		40		500	MSPS
Resolution	1		12			Bits
SUPPLY						
AVDD33			3.15	3.3	3.45	V
AVDDC, A	VDD18, DVDD, DVDDLVDS		1.7	1.8	1.9	V
IOVDD			1.7	1.8	3.45	V
POWER S	UPPLY					
I _{AVDD33}	3.3V Analog supply current			297	330	mA
I _{AVDD18}	1.8V Analog supply current			84	100	mA
I _{AVDDC}	1.8V Clock supply current			26	45	mA
I _{DVDD}	1.8V Digital supply current	Auto correction enabled		230	260	mA
I _{DVDD}	1.8V Digital supply current	Auto correction disabled		106		mA
I _{DVDD}	1.8V Digital supply current	Auto correction disabled, decimation filter enabled		135		mA
I _{DVDDLVDS}	1.8V LVDS supply current			140	170	mA
I _{IOVDD}	1.8V I/O Voltage supply current			1	2	mA
P _{dis}	Total power dissipation	Auto correction enabled, decimation filter disabled		1.84		W
P _{dis}	Total power dissipation	Auto correction disabled, decimation filter disabled		1.62		W
PSRR		250 kHz to 500 MHz	40			dB
Shut-down	power dissipation			7		mW
Shut-down	wake up time			2.5		ms
Standby po	ower dissipation			7		mW
Standby wa	ake up time			100		μs
Doop alaar	modo nower discipation	Auto correction disabled		282		mW
Deep-sleep mode power dissipation		Auto correction enabled		370		mW
Deep-sleep	o mode wakeup time			20		μs
Light close	mode power discipation	Auto correction disabled		549		mW
∟ignt-sieep	mode power dissipation	Auto correction enabled		650		mW
Light-sleep	mode wakeup time			2		μs

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STRUMENTS

EXAS

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ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^{\circ}$ C, full temperature range is $T_{MIN} = -40^{\circ}$ C to $T_{MAX} = 85^{\circ}$ C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD3V = 3.3V, AVDD/DRVDD/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ANALOG INPUTS	· ·	L. L			
Differential input full-scale			1.0	1.25	Vpp
Input common mode voltage			1.9	±0.1	V
Input resistance	Differential at DC		1		kΩ
Input capacitance	Each input to GND		2		pF
VCM common mode voltage output			1.9		V
Analog input bandwidth (3dB)			1200		MHz
DYNAMIC ACCURACY					
Offeet Error	Auto correction disabled	-20	-7.5	20	mV
Offset Error	Auto correction enabled	-1	0	1	mV
Offset temperature coefficient			-611		µV/°C
Gain error		-5		5	%FS
Gain temperature coefficient			0.005		%FS/°C
Differential nonlinearity	f _{IN} = 230 MHz	-1	±0.9	2	LSB
Integral nonlinearity	f _{IN} = 230 MHz	-5	±1.5	5	LSB
CLOCK INPUT					
Input clock frequency		40		500	MHz
Input clock amplitude			2		Vpp
Input clock duty cycle		40%	50%	60%	
Internal clock biasing			0.9		V



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ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^{\circ}$ C, full temperature range is $T_{MIN} = -40^{\circ}$ C to $T_{MAX} = 85^{\circ}$ C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	MIN TYP	MAX	UNITS	
Auto Co	rrection			Enabled	Disabled		Vpp	
DYNAMI	C AC CHARACTERISTICS ⁽¹⁾	-						
		f _{IN} = 10 MHz		60.8	60.8			
		f _{IN} = 100 MHz		60.7	60.8			
SNR	Signal to Noise Ratio	f _{IN} = 230 MHz	59	60.6	60.7		dBFS	
		f _{IN} = 450 MHz		60.2	60.6			
		f _{IN} = 700 MHz		59.4	60.1			
		f _{IN} = 10 MHz		84	86			
		f _{IN} = 100 MHz		84	82			
HD2,3	Second and third harmonic distortion	f _{IN} = 230 MHz	70	80	83		dBc	
	distortion	f _{IN} = 450 MHz		82	84			
		f _{IN} = 700 MHz		76	74			
		f _{IN} = 10 MHz		77	78			
	Spur Free Dynamic Range	f _{IN} = 100 MHz		77	78			
Non HD2,3	(excluding second and third harmonic distortion)	f _{IN} = 230 MHz	70	77	77		dBc	
102,5		f _{IN} = 450 MHz		74	75			
		f _{IN} = 700 MHz		70	71			
	Fs/2-Fin interleaving spur	f _{IN} = 10 MHz		92	80			
		f _{IN} = 100 MHz		83	79			
IL		f _{IN} = 230 MHz	70	83	79		dBc	
		f _{IN} = 450 MHz		79	76			
		f _{IN} = 700 MHz		75	73			
		f _{IN} = 10 MHz		60.6	60.7			
		f _{IN} = 100 MHz		60.6	60.7			
SINAD	Signal to noise and distortion ratio	f _{IN} = 230 MHz	57.5	60.5	60.7		dBFS	
	1410	f _{IN} = 450 MHz		60.1	60.5			
		f _{IN} = 700 MHz		59.3	60			
		f _{IN} = 10 MHz		76.3	79.0			
		f _{IN} = 100 MHz		76.5	77.6			
THD	Total Harmonic Distortion	f _{IN} = 230 MHz	68	77.4	78.1		dBc	
		f _{IN} = 450 MHz		76.3	77.9			
		f _{IN} = 700 MHz		73.4	72.9			
	later modulation distortion	F _{in} = 129.5 and 130.5 MHz, -7 dBFS		82	82			
IMD3	Inter modulation distortion	F _{in} = 349.5 and 350.5 MHz, -7 dBFS		80	80		dBFS	
	Crosstalk			90	90		dB	
ENOB	Effective number of bits	f _{IN} = 230 MHz		9.8	9.8		LSB	

(1) SFDR and SNR calculations do not include the DC or Fs/2 bins when Auto Correction is disabled.



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ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^{\circ}$ C, full temperature range is $T_{MIN} = -40^{\circ}$ C to $T_{MAX} = 85^{\circ}$ C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OVER	-DRIVE RECOVERY ERROI	2				
	Input overload recovery	Recovery to within 5% (of final value) for 6dB overload with sine wave input		2		ns
SAMP	LE TIMING CHARACTERIS	TICS			i.	
rms	Aperture Jitter	Sample uncertainty		100		fs rms
		ADC sample to digital output, auto correction disabled		38		Clock
		ADC sample to digital output, auto correction enabled		50		Cycles
	Data Latency	ADC sample to digital output, Decimation filter enabled, Auto correction disabled		74		Sampling clock Cycles
	Over-range Latency	ADC sample to over-range output		12		Clock Cycles

ELECTRICAL CHARACTERISTICS

The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
DIGITA	L INPUTS – SRESET, SCLK, SDE	NB, SDIO, ENABLE				
	High-level input voltage	All digital inputs support 1.8V and 3.3V logic	0.7 x IOVDD			V
	Low-level input voltage	levels.			0.3 x IOVDD	V
	High-level input current		-50		200	μA
	Low-level input current		-50		50	μA
	Input capacitance			5		pF
DIGITA	L OUTPUTS – SDO					
	High-level output voltage	I _{load} = -100 μA	IOVDD – 0.2			V
	nigh-level output voltage	I _{load} = -2 mA	0.8 x IOVDD			v
		$I_{load} = 100 \ \mu A$			0.2	
	Low-level output voltage	I _{load} = 2 mA			0.22 x IOVDD	V
DIGITA	L INPUTS – SYNCP/N					
V _{ID}	Differential input voltage		250	350	450	mV
V _{CM}	Input common mode voltage		1.125	1.2	1.375	V
t _{SU}			500			ps
DIGITA	L OUTPUTS – DA[11:0]P/N, DAC	LKP/N, OVRAP/N, SYNCOUTP/N, DB[11:0]P/N,	DBCLKP/N, OV	RBP/N		
V _{OD}	Output differential voltage	I _{OUT} = 3.5 mA	250	350	450	mV
V _{OCM}	Output common mode voltage	I _{OUT} = 3.5 mA	1.125	1.25	1.375	V
t _{suA}		F_s = 500 Msps, Data valid to zero-crossing of DACLK	600	800		ps
t _{hA}		$F_s = 500$ Msps, Zero-crossing of DACLK to data becoming invalid	600	790		ps
t _{suB}		F_s = 500 Msps, Data valid to zero-crossing of DBCLK	700	900		ps
t _{hB}		F _s = 500 Msps, Zero-crossing of DBCLK to data becoming invalid	500	600		ps

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ELECTRICAL CHARACTERISTICS (continued)

The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
t _{PD}	$F_s = 500$ Msps, CLKIN falling edge to DACLK, DBCLK rising edge	3.28	3.48	3.74	ns
t _{RISE}	10% - 90%	100	150	200	ps
t _{FALL}	90% - 10%	100	150	200	ps

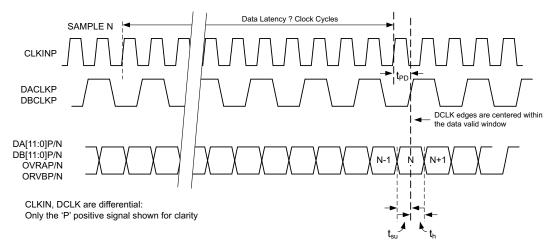
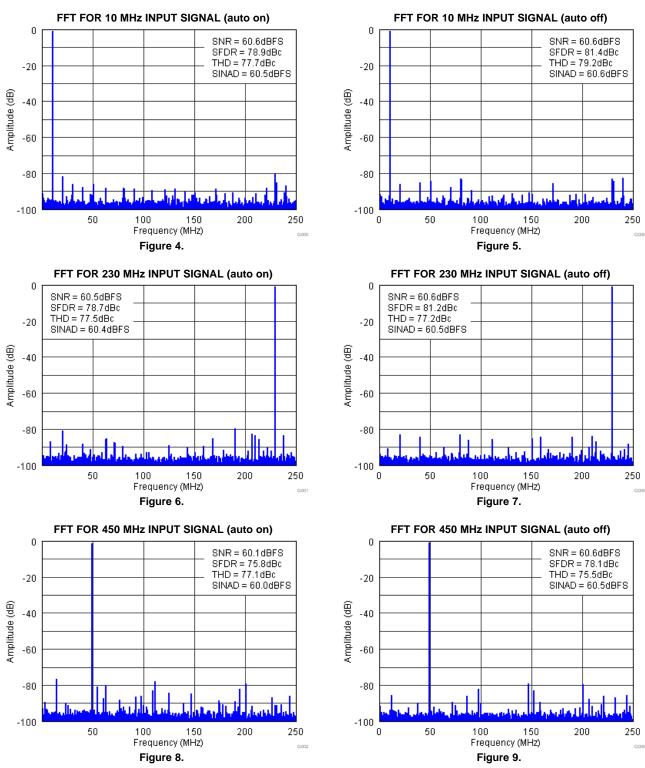


Figure 3. Timing Diagram for 12-bit DDR Output



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TYPICAL CHARACTERISTICS

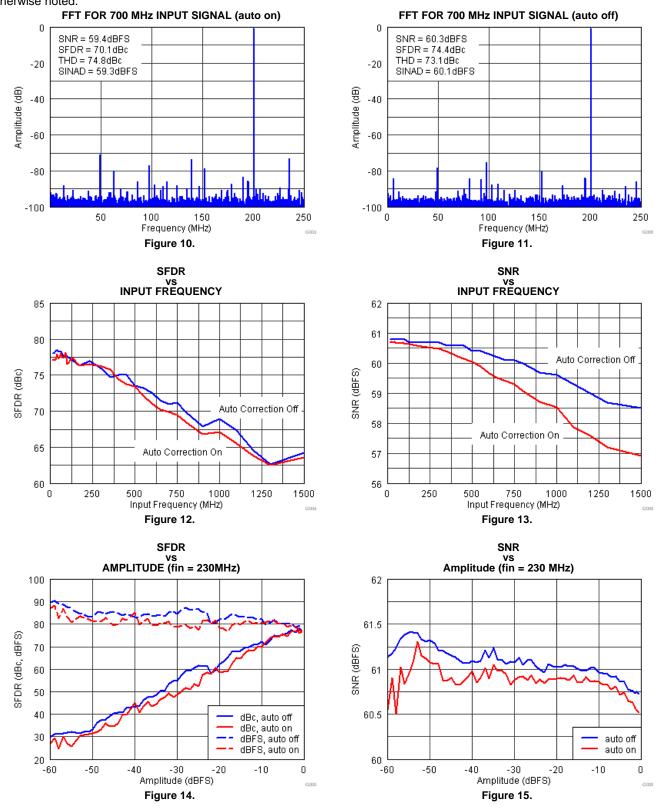




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TYPICAL CHARACTERISTICS (continued)

Typical values at TA = +25°C, full temperature range is T_{MIN} = -40°C to T_{MAX} = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

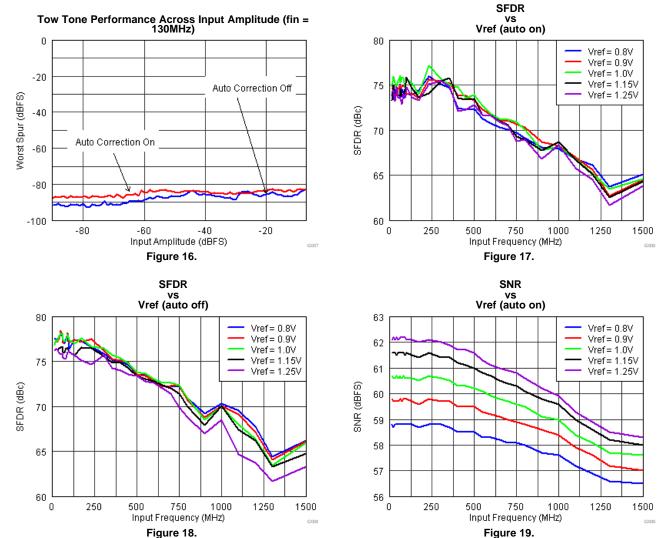


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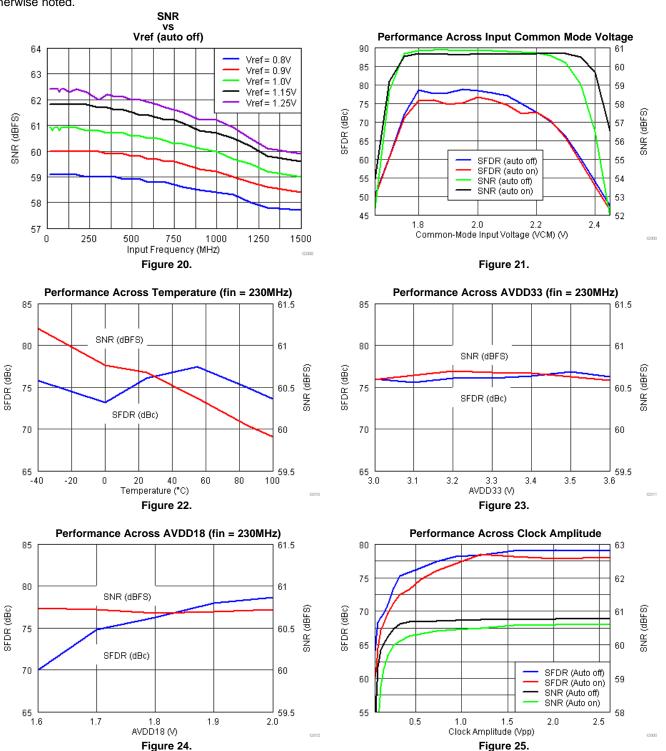
TYPICAL CHARACTERISTICS (continued)



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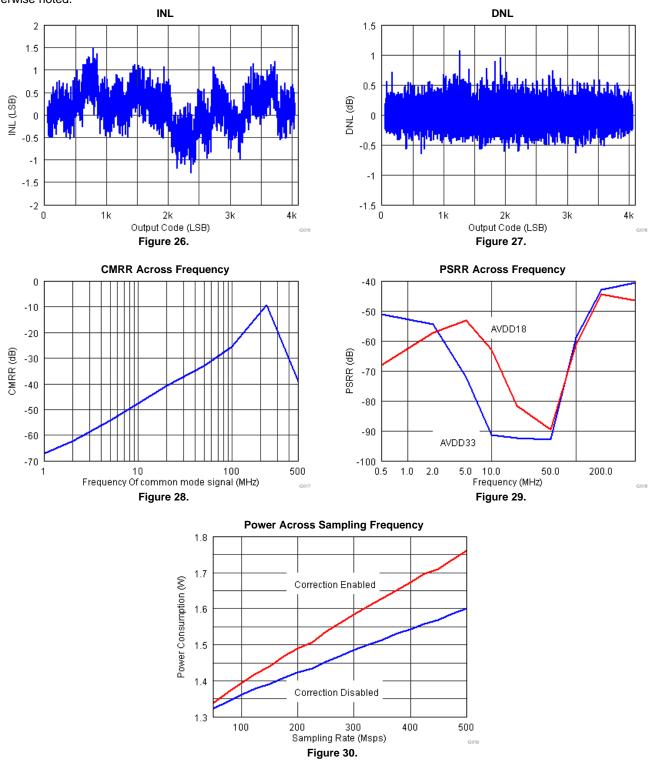
TYPICAL CHARACTERISTICS (continued)





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TYPICAL CHARACTERISTICS (continued)



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TYPICAL CHARACTERISTICS (continued)

Typical values at TA = +25°C, full temperature range is T_{MIN} = -40°C to T_{MAX} = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

SFDR Across Input and Sampling Frequencies (auto on)

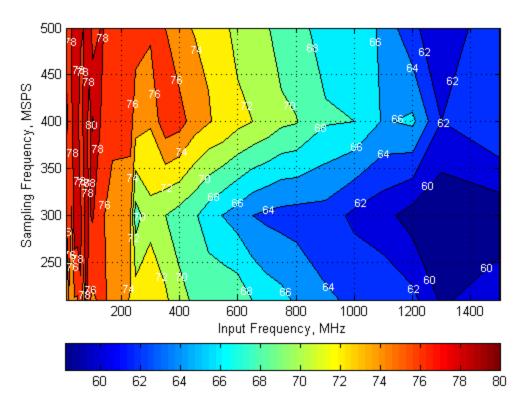


Figure 31.



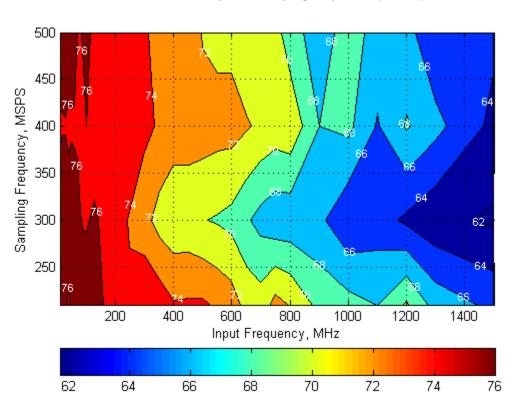
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TYPICAL CHARACTERISTICS (continued)

Typical values at TA = +25°C, full temperature range is T_{MIN} = -40°C to T_{MAX} = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.



SFDR Across Input and Sampling Frequencies (auto off)

Figure 32.

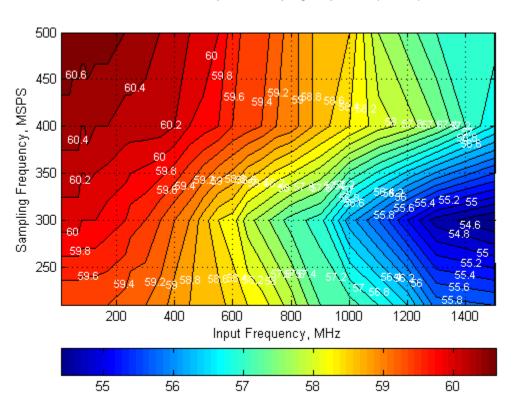
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TYPICAL CHARACTERISTICS (continued)

Typical values at TA = +25°C, full temperature range is T_{MIN} = -40°C to T_{MAX} = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.



SNR Across Input and Sampling Frequencies (auto on)

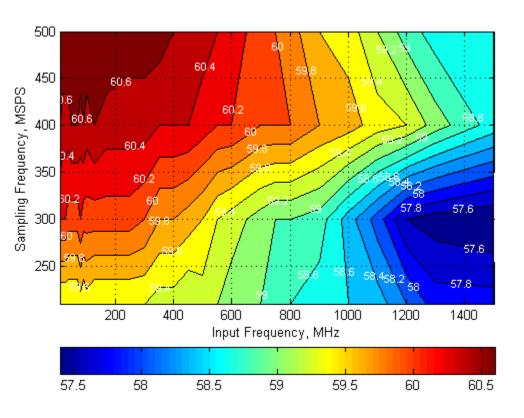
Figure 33.



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TYPICAL CHARACTERISTICS (continued)

Typical values at TA = +25°C, full temperature range is T_{MIN} = -40°C to T_{MAX} = +85°C, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.



SNR Across Input and Sampling Frequencies (auto on)

Figure 34.



FEATURES

POWER DOWN MODES

The ADS5404 can be configured via SPI write (address x37) to a stand-by, light or deep sleep power mode which is controlled by the ENABLE pin. The sleep modes are active when the ENABLE pin goes low. Different internal functions stay powered up which results in different power consumption and wake up time between the two sleep modes.

Sleep mode	Wake up time	Power Consumption Auto correction disabled	Power Consumption Auto correction enabled
Complete Shut Down	2.5 ms	7mW	7mW
Stand-by	100µs	7mW	7mW
Deep Sleep	20µs	282mW	370mW
Light Sleep	2µs	549mW	650mW

TEST PATTERN OUTPUT

The ADS5404 can be configured to output different test patterns that can be used to verify the digital interface is connected and working properly. To enable the test pattern mode, the high performance mode 1 has to be disabled first via SPI register write. Then different test patterns can be selected by configuring registers x3C, x3D and x3E. All three registers must be configured for the test pattern to work properly.

First set HP1 = 0 (Addr 0x01, D01)

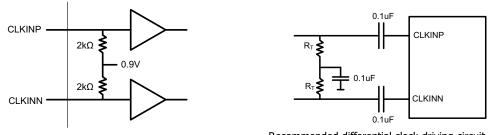
Register Address	All 0s	All 1s	Toggle (0xAAA => 0x555)	Toggle (0xFFF => 0x000)
0x3C	0x8000	0xBFFC	0x9554	0xBFFC
0x3D	0x0000	0x3FFC	0x2AA8	0x0000
0x3E	0x0000	0x3FFC	0x1554	0x3FFC

Register Address								Custom	Pattern	1						
	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
x3C	1	0													0	0
x3D	0	0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	0	0
x3E	0	0													0	0

For normal operation, set HP1 = 1 (Addr 0x01, D01) and 0x3C, 0x3D, 0x3E all to 0.

CLOCK INPUT

The ADS5404 clock input can be driven differentially with a sine wave, LVPECL or LVDS source with little or no difference in performance. The common mode voltage of the clock input is set to 0.9V using internal $2k\Omega$ resistors. This allows for AC coupling of the clock inputs. The termination resistors should be placed as close as possible to the clock inputs in order to minimize signal reflections and jitter degradation.



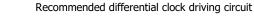


Figure 35. Recommended Differential Clock Driving Circuit



(2)

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SNR AND CLOCK JITTER

The signal to noise ratio of the ADC is limited by three different factors: the quantization noise is typically not noticeable in pipeline converters and is 72dB for a 12bit ADC. The thermal noise limits the SNR at low input frequencies while the clock jitter sets the SNR for higher input frequencies.

$$SNR_{ADC}[dBc] = -20 \times \log_{10} \left(10 - \frac{SNR_{Quantization}Noise}{20} \right)^{2} + \left(10 - \frac{SNR_{ThermalNoise}}{20} \right)^{2} + \left(10 - \frac{SNR_{Jitter}}{20} \right)^{2}$$
(1)

The SNR limitation due to sample clock jitter can be calculated as following:

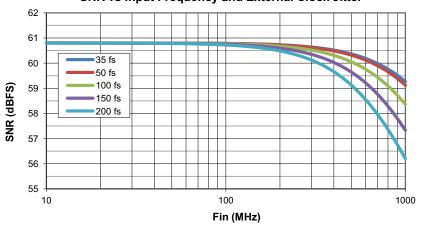
$$SNR_{Jitter} [dBc] = -20 \times log(2\pi \times f_{IN} \times t_{Jitter})$$

The total clock jitter (TJitter) has three components – the internal aperture jitter (100fs for ADS5404) which is set by the noise of the clock input buffer, the external clock jitter and the jitter from the analog input signal. It can be calculated as following:

$$T_{\text{Jitter}} = \sqrt{\left(T_{\text{Jitter,Ext.Clock_Input}}\right)^2 + \left(T_{\text{Aperture}_ADC}\right)^2}$$
(3)

External clock jitter can be minimized by using high quality clock sources and jitter cleaners as well as bandpass filters at the clock input while a faster clock slew rate improves the ADC aperture jitter.

The ADS5404 has a thermal noise of 60.8 dBFS and internal aperture jitter of 100fs. The SNR depending on amount of external jitter for different input frequencies is shown in the following figure.



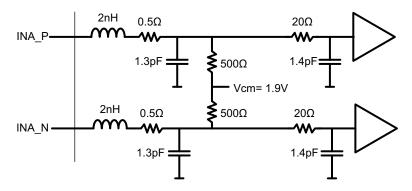
SNR vs Input Frequency and External Clock Jitter



ANALOG INPUTS

The ADS5404 analog signal inputs are designed to be driven differentially. The analog input pins have internal analog buffers that drive the sampling circuit. As a result of the analog buffer, the input pins present a high impedance input across a very wide frequency range to the external driving source which enables great flexibility in the external analog filter design as well as excellent 50Ω matching for RF applications. The buffer also helps to isolate the external driving circuit from the internal switching currents of the sampling circuit which results in a more constant SFDR performance across input frequencies.

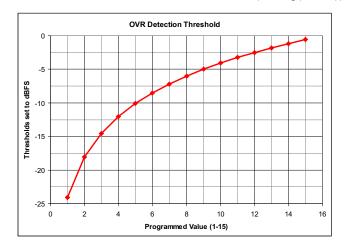
The common-mode voltage of the signal inputs is internally biased to 1.9V using 500Ω resistors which allows for AC coupling of the input drive network. Each input pin (INP, INM) must swing symmetrically between (VCM + 0.25V) and (VCM – 0.25V), resulting in a 1.0Vpp (default) differential input swing. The input sampling circuit has a 3dB bandwidth that extends up to 1.2GHz.



OVER-RANGE INDICATION

The ADS5404 provides a fast over-range indication on the OVRA/B pins. The fast OVR is triggered if the input voltage exceeds the programmable overrange threshold and it gets presented after just 12 clock cycles enabling a quicker reaction to an overrange event. The OVR threshold can be configured using SPI register writes.

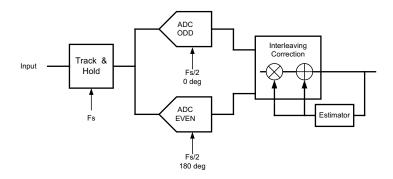
The input voltage level at which the overload is detected is referred to as the threshold and is programmable using the Over-range threshold bits. The threshold at which fast OVR is triggered is (full-scale \times [the decimal value of the FAST OVR THRESH bits] /16). After reset, the default value of the over-range threshold is set to 15 (decimal) which corresponds to a threshold of 0.56dB below full scale (20*log(15/16)).





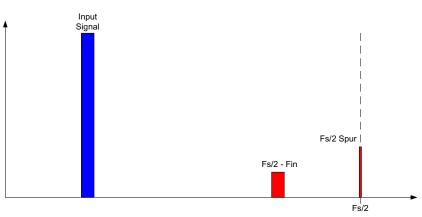
INTERLEAVING CORRECTION

Each of the two data converter channels consists of two interleaved ADCs each operating at half of the ADC sampling rate but 180° out of phase from each other. The front end track and hold circuitry is operating at the full ADC sampling rate which minimizes the timing mismatch between the two interleaved ADCs. In addition the ADS5404 is equipped with internal interleaving correction logic that can be enabled via SPI register write.



The interleaving operation creates 2 distinct and interleaving products:

- Fs/2 Fin: this spur is created by gain timing mismatch between the ADCs. Since internally the front end track and hold is operated at the full sampling rate, this component is greatly improved and mostly dependent on gain mismatch.
- Fs/2 Spur: due to offset mismatch between ADCs

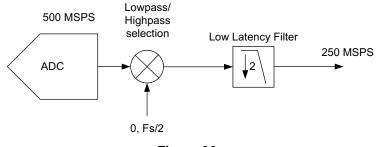


The auto correction loop can be enabled via SPI register write in address 0x01. By default it is disabled for lowest possible power consumption. The DC correction function can be enabled in 0x03 & 0x1A for chA and chB respectively. The default settings for the auto correction function should work for most applications. However please contact Texas Instruments if further fine tuning of the algorithm is required.

The auto correction function yields best performance for input frequencies below 250MHz. For input frequencies greater than 250MHz it is recommended to disable the auto gain correction loop.

DECIMATION FILTER

Each channel has a digital filter in the data path as shown in Figure 36. The filter can be programmed as a low-pass or a high-pass filter and the normalized frequency response of both filters is shown in Figure 37.





The decimation filter response has a 0.1dB pass band ripple with approximately 41% pass-band bandwidth. The stop-band attenuation is approximately 40dB.

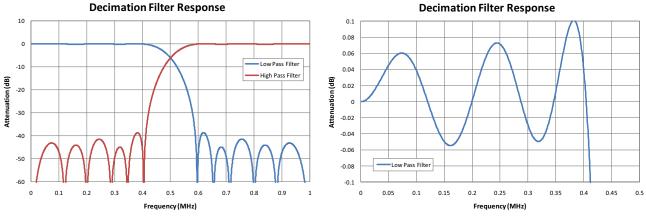
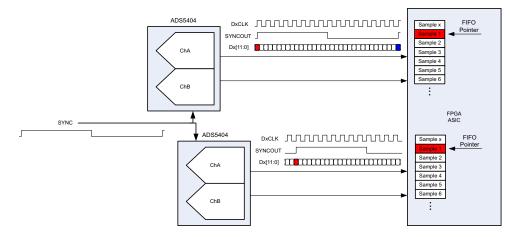


Figure 37.



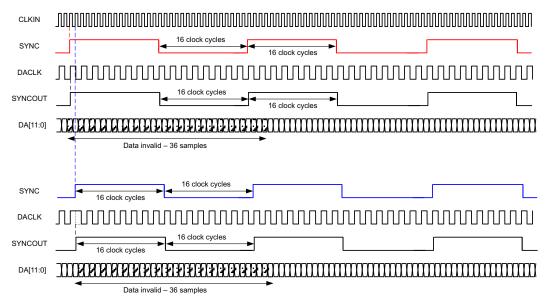
MULTI DEVICE SYNCHRONIZATION

The ADS5404 simplifies the synchronization of data from multiple ADCs in one common receiver. Upon receiving the initial SYNC input signal, the ADS5404 resets all the internal clocks and digital logic while also starting a SYNCOUT signal which operates on a 5bit counter (32 clock cycles). Therefore by providing a common SYNC signal to multiple ADCs their output data can be synchronized as the SYNCOUT signal marks a specific sample with the same latency in all ADCs. The SYNCOUT signal then can be used in the receiving device to synchronize the FIFO pointers across the different input data streams. Thus the output data of multiple ADCs can be aligned properly even if there are different trace lengths between the different ADCs.



The SYNC input signal should be a periodic signal repeating every 32 CLKIN clock cycles. It gets registered on the rising edge of the ADC input clock (CLKIN). Upon registering the initial rising edge of the SYNC signal, the internal clocks and logic get reset which results in invalid output data for 36 samples (1 complete sync cycle and 4 additional samples). The SYNCOUT signal starts with the next output clock (DACLK) rising edge and operates on a 5-bit counter independent from the SYNC signal frequency and duty cycle.

Since the ADS5404 output interface operates with a DDR clock, the synchronization can happen on the rising edge or falling edge sample. Synchronization on the falling edge sample will result in a half cycle clock stretch of DA/BCLK. For convenience the SYNCOUT signal is available on the ChA/B output LVDS bus. When using decimation the SYNCOUT signal still operates on 32 clock cycles of CLKIN but since the output data is decimated by 2, only the first 18 samples should be discarded.





PROGRAMMING INTERFACE

The serial interface (SIF) included in the ADS5404 is a simple 3 or 4 pin interface. In normal mode, 3 pins are used to communicate with the device. There is an enable (SDENB), a clock (SCLK) and a bi-directional IO port (SDIO). If the user would like to use the 4 pin interface one write must be implemented in the 3 pin mode to enable 4 pin communications. In this mode, the SDO pin becomes the dedicated output. The serial interface has an 8-bit address word and a 16-bit data word. The first rising edge of SCLK after SDENB goes low will latch the read/write bit. If a high is registered then a read is requested, if it is low then a write is requested. SDENB must be brought high again before another transfer can be requested. The signal diagram is shown below:

Register Initialization

After power up, the internal registers must be initialized to the default values. This initialization can be accomplished in one of two ways:

- 1. Either through hardware reset by applying a low pulse on SRESET pin
- 2. By applying a software reset. When using the serial interface, a reset can be performed by addressing register x2C. This setting initializes the internal registers to the default values and then self-resets the RESET register to 0. In this case the SRESET pin can be kept high.

Serial Register Write

The internal register of the ADS5404 can be programmed following these steps:

- 1. Drive SDENB pin low
- 2. Set the R/W bit to '0' (bit A7 of the 8 bit address)
- 3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be written
- 4. Write 16bit data which is latched on the rising edge of SCLK

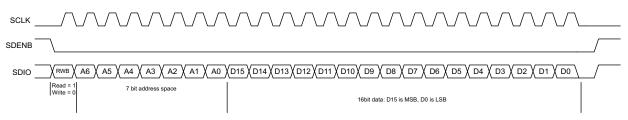


Figure 38. Serial Register Write Timing Diagram

	PARAMETER	MIN	TYP ⁽¹⁾	MAX	UNIT
f _{SCLK}	SCLK frequency (equal to 1/tSCLK)	>DC		20	MHz
t _{SLOADS}	SDENB to SCLK setup time	25			ns
t _{SLOADH}	SCLK to SDENB hold time	25			ns
t _{DSU}	SDIO setup time	25			ns
t _{DH}	SDIO hold time	25			ns

(1) Typical values at +25°C; minimum and maximum values across the full temperature range: TMIN = -40°C to TMAX = +85°C, AVDD3V = 3.3V, AVDD, DRVDD = 1.9V, unless otherwise noted.



Serial Register Readout

The device includes a mode where the contents of the internal registers can be read back using the SDO/SDIO pins. This read-back mode may be useful as a diagnostic check to verify the serial interface communication between the external controller and the ADC.

- 1. Drive SDENB pin low
- 2. Set the RW bit (A7) to '1'. This setting disables any further writes to the registers
- 3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be read.
- 4. The device outputs the contents (D15 to D0) of the selected register on the SDO/SDIO pin
- 5. The external controller can latch the contents at the SCLK rising edge.
- 6. To enable register writes, reset the RW register bit to '0'.

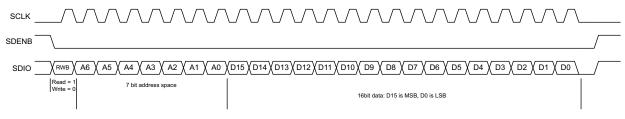


Figure 39. Serial Register Read Timing Diagram



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SERIAL REGISTER MAP⁽²⁾

Register Address								Regist	er Data							
A7–A0 IN HEX	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	Decimat ion Filter EN	0	ChA High/ Low Pass	0	0	ChB High/ Low Pass	0	0	0	0	0	0	0	0	0
1	ChA Corr EN	0	0	0	0	0	ChB Corr EN	0	0	0	0	0	Data Format	0	Hp Mode1	0
2	0	0	0	0	0		Over-range	e threshold		0	0	0	0	0	0	0
3	0	Start Auto Corr ChA	0	0	1	0	1	1	0	0	0	1	1	0	0	0
Е								Sync	Select							
F		Sync S	Select		0	0	0	0	0		VREF Set		0	0	0	0
1A	0	Start Auto Corr ChB	0	0	1	0	1	1	0	0	0	1	1	0	0	0
2B	0	0	0	0	0	0	0				T	emp Sens	or			
2C				Į.				Re	set							
37			Sleep	Modes			0	0	0	0	0	0	0	0	0	0
38					HP Mode2		1		1	BIAS EN	SYNC EN	LP Mode 1	0	0	0	0
ЗA	LVDS	Current Str	rength	LVDS	S SW		al LVDS ination	0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN
66							L	VDS Outp	ut Bus A E	N						
67							L	VDS Outp	ut Bus B E	N						

(2) Multiple functions in a register can be programmed in a single write operation.

DESCRIPTION OF SERIAL INTERFACE REGISTERS

Register Address								Regis	ter Data	1						
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	Deci matio n Filter EN	0	ChA High/ Low Pass	0	0	ChB High/ Low Pass	0	0	0	0	0	0	0	0	0

D15 **3/4 Wire SPI** Enables 4-bit serial interface when set Default 0

- 0 3 wire SPI is used with SDIO pin operating as bi-directional I/O port
- 1 4 wire SPI is used with SDIO pin operating as data input and SDO pin as data output port.
- D14 **Decimation** 2x decimation filter is enabled when bit is set **Filter EN** Default 0
- 0 Normal operation with data output at full sampling rate
- 1 2x decimation filter enabled
- D12 ChA High/Low (Decimation filter must be enabled first: set bit D14) Pass Default 0
- 0 Low Pass



D1

HP

D0

0

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- 1 **High Pass**
- D9 **ChB High/Low** (Decimation filter must be enabled first: set bit D14) Pass Default 0
- 0 Low Pass
- 1 **High Pass**
- Register **Register Data** Address A7-A0 in hex D15 D14 D13 D12 D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 ChB ChA 0 1 1 0 0 0 0 0 0 0 0 Data 0 Corr Corr Format Mode1 ΕN ΕN
- D15 ChA Corr EN (should be enabled for maximum performance)

Default 0

- 0 auto correction disabled
- 1 auto correction enabled
- D9 ChB Corr EN (should be enabled for maximum performance) Default 0
- 0 auto correction disabled
- 1 auto correction enabled
- D3 **Data Format** Default 0
- 0 Two's complement
- 1 **Offset Binary**
- HP Mode 1 D1

Default 0

1 Must be set to 1 for optimum performance



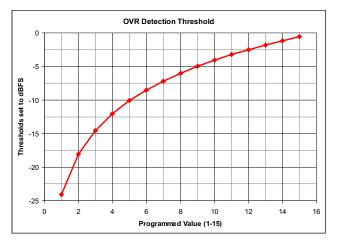
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Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2	0	0	0	0	0	Ov	er-rang	e thresh	old	0	0	0	0	0	0	0

D14 Read back 1.

D10-D7 **Over-range threshold** The over-range detection is triggered 12 output clock cycles after the overload condition occurs. The threshold at which the OVR is triggered = $1.0V \times [\text{decimal value of <Over-range threshold>]/16}$. After power up or reset, the default value is 15 (decimal) which corresponds to a OVR threshold of 0.56dB below fullscale (20*log(15/16)). This OVR threshold is applicable to both channels.

Default 1111



Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3	0	Start Auto Corr ChA	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14 Start Auto Corr ChA Starts DC offset and gain correction loop for ChA

Default 1

0 Starts the DC offset and gain correction loop

1 Clears the DC offset correction value to 0 and gain value to 1

D11, 9, 8, 4, 3 Must be set to 1 for maximum performance Default 1



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Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
E								Sync	Select							

D15-D2	Sync Select Default 1010 1010 1010 10	Sync selection for the clock generator block (also need to see address 0x0F)
0000 0000 0000 00	Sync is disabled	
0101 0101 0101 01	Sync is set to one sho	ot (one time synchronization only)
1010 1010 1010 10	Sync is derived from S	SYNC input pins
1111 1111 1111 11	not supported	

Register Address						Register Data														
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0				
F		Sync Select 0 0 0 0 0 VREF Sel 0 0 0 0																		

block

D15-D12	Sync Select Default 1010	Sync selection for the clock generator
0000	Sync is disabled	
0101	Sync is set to one shot	(one time synchronization only)
1010	Sync is derived from SY	NC input pins
1111	not supported	
D6-D4	VREF SEL Default 000	Internal voltage reference selection
000	1.0V	
001	1.25V	
010	0.9V	
011	0.8V	
100	1.15V	
Others	external reference	

Register Address		Register Data														
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1A	0	Start Auto Corr ChB	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14	Start Auto Corr ChB Default 1	Starts DC offset and gain correction loop for ChB
0 1	Starts the DC offset and gain Clears DC offset correction va	•
D11, 9, 8, 4, 3	Must be set to 1 for maximun Default 1	n performance

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Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2B	0	0	0	0	0	0	0				Те	mp Sen	sor			

D8-D0 Ten

Temp Sensor

Internal temperature sensor value – read only

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2C								Re	set							

D15-D0 Reset Default This is a software reset to reset all SPI registers to their default value. Self clears to 0.

1101001011110000

0000

Perform software reset

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
37		Sleep Modes 0 <th< td=""></th<>														

D15-D14	Sleep Modes Default 00	S
000000	Complete shut down	٧
100000	Stand-by mode	٧
110000	Deep sleep mode	٧
110101	Light sleep mode	٧

Sleep mode selection which is controlled by the ENABLE pin. Sleep modes are active when ENABLE pin goes low.

t down Wake up time 2.5 ms le Wake up time 100 μs lode Wake up time 20 μs ode Wake up time 2 μs



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Register Address		Register Data														
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
38				н	P Mode	2				Bias EN	SYNC EN	LP Mode 1	0	0	0	0

D15-D7 1	HP Mode 2 Default 111111111 Set to 1 for normal operation	
1		
D6	BIAS EN Default 1	Enables internal fuse bias voltages – can be disabled after power up to save power.
0	Internal bias powered down	
1	Internal bias enabled	
D5	SYNC EN Default 1	Enables the SYNC input buffer.
0	SYNC input buffer disabled	
1	SYNC input bffer enabled	
D4	LP Mode 1 Default 1	Low power mode 1 to disable unused internal input buffers.
0	Internal input buffer disabled	
1	Internal input buffer disabled	

ADS5404

Register Address

A7-A0 in hex

3A

D15-D13

000

001

010

011

01

11 D10-D9

00

01

10

11

D4

0

1

D3

0

1 D1

0

1

D0

0 1

D12-D11



SLAS945A - APRIL 2013 - REVISED AUGU

D15

LVDS Current

Strength Default 000

2 mA

2.25 mA

2.5 mA

2.75 mA

LVDS SW

Default 01

2 mA to 2.75 mA 3mA to 3.75mA

Internal LVDS

Termination Default 00

2 kΩ

200 Ω

200 Ω

100 Ω

DACLK EN

DBCLK EN

Default 1

OVRA EN

OVRB EN

Default 1

Default 1

Default 1

D14 D13

DACLK output buffer powered down

DBCLK output buffer powered down DBCLK output buffer enabled

OVRA output buffer powered down

OVRB output buffer powered down

OVRA output buffer enabled

OVRB output buffer enabled

DACLK output buffer enabled

Enable DACLK output buffer

Enable DBCLK output buffer

Enable OVRA output buffer

Enable OVRB output buffer

LVDS Current

Strength

ISED /	AUGL	IST 2013	3										ww	w.ti.com
						Re	gister I	Data						
4 C	013	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Curren	t	LVDS	S SW	LV	rnal DS nation	0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN
t	L	/DS ou	tput cu	rrent str	ength.									
100		mA												
101 110	-	25 mA 5 mA												
111		75 mA												
			ernal sw	vitch set	tting – c	orrect r	ange m	iust be	set for :	setting in [D15-D13			
mA														
A S	In	ternal t	erminat	ion										



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Register Address								Registe	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
66	LVDS Output Bus A EN															

D15-D10	LVDS Output Bus A EN Default FFFF	Individual LVDS output pin power down for channel A
0	Output is powered down	
1	Output is enabled	
D15	Pins N7, P7 (no connect pins) power savings	which are not used and should be powered down for
D14	Pins N6, P6 (no connect pins) power savings	which are not used and should be powered down for
D13	SYNCOUTP/N (pins P5, N5)	
D12	Pins N4, P4 (no connect pins) power savings	which are not used and should be powered down for

D11-D0 corresponds to DA11-D0

Register Address								Regist	er Data							
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
67		LVDS Output Bus B EN														

D15-D10	LVDS Output Bus B EN Default FFFF	ndividual LVDS output pin power down for channel B
0	Output is powered down	
1	Output is enabled	
D15	Pins G3, G4 (no connect pins) v power savings	which are not used and should be powered down for
D14	Pins F3, F4 (no connect pins) w power savings	hich are not used and should be powered down for
D13	SYNCOUTP/N (pins F1, F2)	
D12	Pins E3, E4 (no connect pins) v power savings	which are not used and should be powered down for
D11-D0	corresponds to DB11-DB0	

REVISION HISTORY

Changes from Original (April 2013) to Revision A

•

•	Changed D11-D10 - corresponds to DA11-DA0 in Register 66 To: D11-D0 -corresponds to DA11-D0	35
•	Changed D11-D10 - corresponds to DB11-DB0 in Register 67 To: D11-D0 -corresponds to DB11-DB0	35

•	Changed D11-D10	- corresponds to DB11-	-DB0 in Register 67	To: D11-D0 -correspor	nds to DB11-DB0		35
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Page



19-Aug-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
ADS5404IZAY	ACTIVE	NFBGA	ZAY	196	160	Green (RoHS & no Sb/Br)	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS5404I	Samples
ADS5404IZAYR	ACTIVE	NFBGA	ZAY	196	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS5404I	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nomina	al

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS5404IZAYR	NFBGA	ZAY	196	1000	330.0	24.4	12.3	12.3	2.3	16.0	24.0	Q1

TEXAS INSTRUMENTS

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PACKAGE MATERIALS INFORMATION

19-Aug-2013

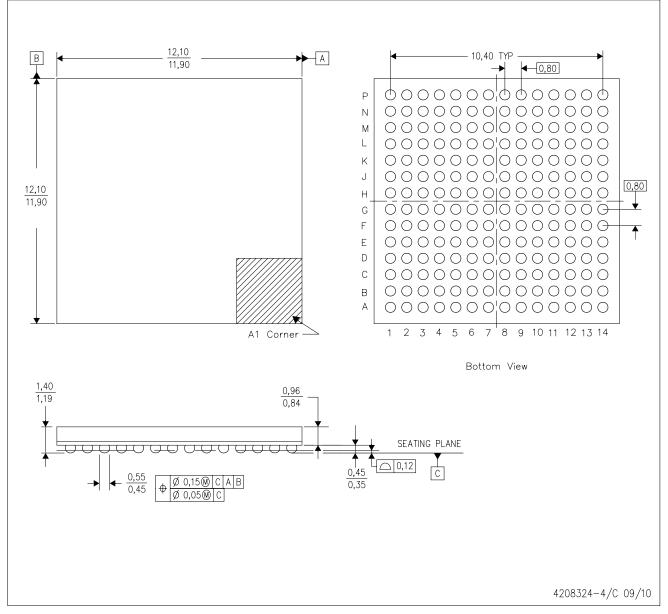


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADS5404IZAYR	NFBGA	ZAY	196	1000	336.6	336.6	31.8

ZAY (S-PBGA-N196)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. This is a Pb-free solder ball design.



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